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10/09/1985  
03/06/02

PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10091985	FILING DATE 03/06/2002	CLASS 356	SUBCLASS 51.2	GAU 2877	EXAMINER LEE
<b>**APPLICANTS:</b> Suzuki Akiyoshi; Sekine Yoshiyuki;					
<b>**CONTINUING DATA VERIFIED:</b> none abt					
<b>** FOREIGN APPLICATIONS VERIFIED:</b> JAPAN 062055/2001(PAT.) 03/06/2001 JAPAN 109998/2001(PAT.) 04/09/2001					
PG-PUB <input type="checkbox"/>		DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>	
Foreign priority claimed: <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met: <input checked="" type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials: <i>LM</i>				ATTORNEY DOCKET NO 1232-4835	
TITLE : Interferometer and interference measurement method					

U.S. DEPT. OF COM. / PAT. & TM-PTO-436 (Rev. 12-94)

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NOTICE OF

04/12

Amount Due

\$1600



DRAWINGS			CLAIMS ALLOWED	
Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
			<b>NOTICE OF ALLOWANCE MAILED</b>	
(Assistant Examiner) _____ (Date) _____				
			<b>ISSUE FEE</b>	
(Primary Examiner) _____ (Date) _____			Amount Due	Date Paid
(Legal Instruments Examiner) _____ (Date) _____			<b>ISSUE BATCH NUMBER</b>	